

标题: Contrast inversion of the apparent barrier height of Pb thin films in scanning tunneling microscopy

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Michael Becker and Richard Berndt Scanning tunneling microscopy measurements of the apparent height of the tunneling barrier are analyzed for Pb islands on Ag(111). The apparent barrier height (ABH) significantly varies with the bias voltage. This bias dependence leads to drastic changes and even inversion of contrast in spatial map ... [Appl. Phys. Lett. 96, 033112 (2010)] published Fri Jan 22, 2010.